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Form PTO-1449 INFORMATION DISCLOSURE CITATION

0630-1891P APPLICANT

APPLICATION NO. 10/743,493

## IN AN APPLICATION

(Use several sheets if necessary)

Se Wan KIM et al.

ATTY. DOCKET NO.

FILING DATE December 23, 2003 GROUP UNASSIGNED

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01/17/2007

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Complete if Known Substitute for form 1449A/B/PTO 10/743,493-Conf. #7784 Application Number INFORMATION DISCLOSURE December 23, 2003 Filing Date STATEMENT BY APPLICANT First Named Inventor Se Wan KIM Art Unit 3661 (Use as many sheets as necessary) Examiner Name M. Marc Sheet 1 of 1 Attorney Docket Number 0630-1891P

			U.S. PA	TENT DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number  Number-Kind Code <sup>2</sup> ( if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Examiner Signature	/Marie Weiskopf/	Date Considered	01/17/2007
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Sub	stitute for form 1449A/B/PT	0			Complete if Known
		•		Application Number	10/743,493-Conf. #007784
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s	TATEMENT E	3Y /	APPLICANT	First Named Inventor	Se Wan KIM
				Art Unit	3661
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Sheet	1	of	1	Attorney Docket Number	0630-1891P

			U.S. PA	TENT DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number  Number-Kind Code <sup>2</sup> ( if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

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Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where Relevant Passages	؞
Initials*	No.1	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)		Applicant of Cited Document	or Relevant Figures Appear	
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Examiner Signature	/Marie Weiskopf/	Date Considered	01/17/2007
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